

# CY621282BN MoBL<sup>®</sup> Automotive 1-Mbit (128 K × 8) Static RAM

### Features

- Temperature Ranges □ Automotive-E: -40 °C to 125 °C
- 4.5 V to 5.5 V operation
- Complementary metal oxide semiconductor (CMOS) for optimum speed/power
- Low active power 137.5 mW (max.) (25 mA)
- Low standby power
   137.5 μW (max.) (25 μA)
- Automatic power-down when deselected
- TTL-compatible inputs and outputs
- Easy memory expansion with  $\overline{CE}_1$ ,  $CE_2$ , and  $\overline{OE}$  options
- Available in Pb-free 32-pin (450 mil-wide) small outline integrated circuit (SOIC) package

### **Functional Description**

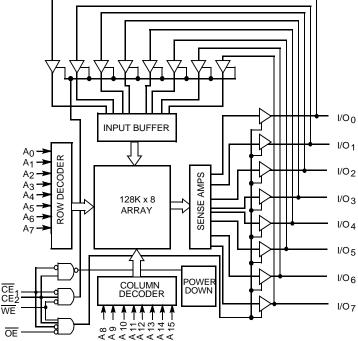
The CY621282BN is a high-performance CMOS static RAM organized as 128K words by 8 bits. Easy memory expansion is provided by an active LOW Chip Enable ( $\overline{CE}_1$ ), an active HIGH Chip Enable ( $\overline{CE}_2$ ), and active LOW Output Enable ( $\overline{OE}$ ). This device has an automatic power-down feature that reduces power consumption by more than 75% when deselected.

<u>Writing</u> to the device is accomplished by taking Chip Enable One  $(\overline{CE}_1)$  and Write Enable (WE) inputs LOW and Chip Enable Two  $(CE_2)$  input HIGH. Data on the eight I/O pins (I/O<sub>0</sub> through I/O<sub>7</sub>) is then written into the location specified on the address pins (A<sub>0</sub> through A<sub>16</sub>).

Reading from the device is accomplished by taking Chip Enable One ( $\overline{CE}_1$ ) and Output Enable ( $\overline{OE}$ ) LOW while forcing Write Enable ( $\overline{WE}$ ) and Chip Enable Two ( $\overline{CE}_2$ ) HIGH. Under these conditions, the contents of the memory location specified by the address pins will appear on the I/O pins.

The eight input/output pins ( $I/O_0$  through  $I/O_7$ ) are placed in a high-impedance state when the device is <u>des</u>elected ( $\overline{CE}_1$  HIGH or  $CE_2$  LOW), the outputs are disabled ( $\overline{OE}$  HIGH), or during a write operation ( $\overline{CE}_1$  LOW,  $CE_2$  HIGH, and  $\overline{WE}$  LOW).

### Logic Block Diagram



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### **Product Portfolio**

Product V <sub>CC</sub> Range (V) Speed (ns)		Voo Bange (V)			Power Dissipation				
		Operating, I <sub>CC</sub> (mA)		Standby, I <sub>SB2</sub> (µA)					
		Min	Тур [1]	Max		Тур [1]	Max	Тур [1]	Мах
CY621282BN	Automotive-E	4.5	5.0	5.5	70	6	25	2.5	25

## **Pin Configuration**

	1 O 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16	32 ] 31 ] 29 ] 28 ] 27 ] 26 ] 27 ] 26 ] 27 ] 26 ] 27 ] 27 ] 28 ] 27 ] 28 ] 27 ] 28 ] 27 ] 28 ] 27 ] 28 ] 27 ] 28 ] 28 ] 27 ] 28 ] 28 ] 28 ] 27 ] 28 ] 28 ] 28 ] 28 ] 27 ] 28 ] 28 ] 28 ] 29 ] 28 ] 28 ] 28 ] 28 ] 29 ] 28 ] 28 ] 28 ] 29 ] 28 ] 28 ] 29 ] 29 ] 28 ] 29 ] 28 ] 29 ] 29 ] 29 ] 20 ] 20 ] 20 ] 20 ] 20 ] 20 ] 20 ] 20	V <sub>CC</sub> A15 <u>CE2</u> WE A13 A8 A9 A11 <u>CE2</u> UZ A13 A8 A9 A11 <u>CE2</u> UZ A13 A8 A9 A11 <u>CE2</u> UZ A13 A8 A9 A11 <u>CE2</u> UZ A15 <u>CE2</u> VE2 A15 A15 A15 A15 A15 A15 A15 A15 A15 A15
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## **Pin Definitions**

I/O Type	Description
Input	A <sub>0</sub> -A <sub>16</sub> . Address inputs
Input/output	I/O <sub>0</sub> -I/O <sub>7</sub> . Data lines. Used as input or output lines depending on operation.
Input/control	WE. Write Enable, Active LOW. When selected LOW, a WRITE is conducted. When selected HIGH, a READ is conducted.
Input/control	CE <sub>1</sub> . Chip Enable 1, Active LOW.
Input/control	CE <sub>2</sub> . Chip Enable 2, Active HIGH.
Input/control	<b>OE</b> . Output Enable, Active LOW. Controls the direction of the I/O pins. When LOW, the I/O pins behave as outputs. When deasserted HIGH, I/O pins are tri-stated, and act as input data pins.
Ground	GND. Ground for the device.
Power supply	V <sub>CC</sub> . Power supply for the device.

#### Note 1. Typical values are included for reference only and are not tested or guaranteed. Typical values are measured at $V_{CC}$ = 5.0 V, $T_A$ = 25 °C.



## **Maximum Ratings**

Exceeding maximum ratings may impair the useful life of the device. These user guidelines are not tested.

Storage temperature65 °C to +150 °C
Ambient temperature with power applied55 °C to +125 °C
Supply voltage on $V_{CC}$ to relative $GND^{[2]}$ –0.5 V to +7.0 V
DC voltage applied to outputs in High Z state $^{[2]}$ 0.5 V to V_{CC} + 0.5 V

DC input voltage <sup>[2, 3]</sup>	–0.5 V to V <sub>CC</sub> + 0.5 V
Current into outputs (LOW)	
Static discharge voltage (per MIL-STD-883, Method 3015)	> 2001 V
Latch-up current	> 200 mA

## **Operating Range**

Range	Ambient Temperature	V <sub>CC</sub>
Automotive-E	–40 °C to +125 °C	$5 \text{ V} \pm 10\%$

## **Electrical Characteristics**

Over the Operating Range

Parameter	Description Test Condit	Tost Conditions		-70		Unit
Farameter		Test conditions	Min	Тур <sup>[4]</sup>	Max	Om
V <sub>OH</sub>	Output HIGH voltage	$V_{CC} = 4.5 \text{ V}, I_{OH} = -1.0 \text{ mA}$	2.4	-	-	V
		$V_{CC} = 5.5 \text{ V}, I_{OH} = -0.1 \text{ mA}$	3.95	-	-	
		$V_{CC} = 5 \text{ V}, \text{ I}_{OH} = -0.1 \text{ mA}$	3.6	-	-	
		$V_{CC} = 4.5 \text{ V}, I_{OH} = -0.1 \text{ mA}$	3.25	-	-	
V <sub>OL</sub>	Output LOW voltage	V <sub>CC</sub> = 4.5 V, I <sub>OL</sub> = 2.1 mA	-	-	0.4	V
V <sub>IH</sub>	Input HIGH voltage		2.2	-	V <sub>CC</sub> + 0.3	V
V <sub>IL</sub>	Input LOW voltage <sup>[2]</sup>		-0.3	-	0.8	V
I <sub>IX</sub>	Input leakage current	$GND \le V_{IN} \le V_{CC}$	-10	-	+10	μA
I <sub>OZ</sub>	Output leakage current	$GND \le V_{IN} \le V_{CC}$ , Output Disabled	-10	-	+10	μΑ
I <sub>CC</sub>	V <sub>CC</sub> operating supply current	$f = f_{MAX} = 1/t_{RC}$ V <sub>CC</sub> = 5.5 V,	-	6	25	mA
		f = 1 MHz I <sub>OUT</sub> = 0 mA		2	12	
I <sub>SB1</sub>	Automatic CE power-down current —TTL inputs	$ \begin{array}{c} V_{CC} = 5.5 \text{ V}, \overline{CE}_1 \geq V_{IH} \text{ or } CE_2 \leq V_{IL}, \\ V_{IN} \geq V_{IH} \text{ or } V_{IN} \leq V_{IL}, \text{ f} = f_{MAX} \end{array} $	-	0.1	2	mA
I <sub>SB2</sub>	Automatic CE power-down current —CMOS inputs	$\begin{array}{l} V_{CC} = 5.5 \ \text{V}, \ \overline{CE}_1 \geq V_{CC} - 0.3 \ \text{V}, \\ \text{or} \ CE_2 \leq 0.3 \ \text{V}, \ \text{V}_{IN} \geq V_{CC} - 0.3 \ \text{V}, \text{or} \\ V_{IN} \leq 0.3 \ \text{V}, \ \text{f} = 0 \end{array}$	-	2.5	25	μA

Notes

V<sub>IL</sub> (min.) = -2.0 V for pulse durations of less than 20 ns.
 No input may exceed V<sub>CC</sub> + 0.5 V.
 Typical values are included for reference only and are not tested or guaranteed. Typical values are measured at V<sub>CC</sub> = 5.0 V, T<sub>A</sub> = 25 °C.



## Capacitance

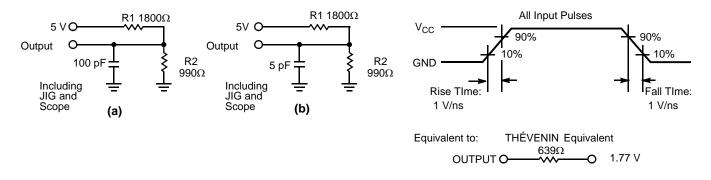
Parameter <sup>[5]</sup>	Description	Test Conditions	Max	Unit
C <sub>IN</sub>	Input capacitance	T <sub>A</sub> = 25 °C, f = 1 MHz, V <sub>CC</sub> = 5.0 V	9	pF
C <sub>OUT</sub>	Output capacitance		9	pF

### **Thermal Resistance**

Parameter <sup>[5]</sup>	Description	Test Conditions	32-pin SOIC	Unit
$\Theta_{JA}$		Test conditions follow standard test methods and procedures for measuring thermal impedance, per EIA /	66.17	°C/W
- 30	Thermal resistance (junction to case)	JESD51.	30.87	°C/W

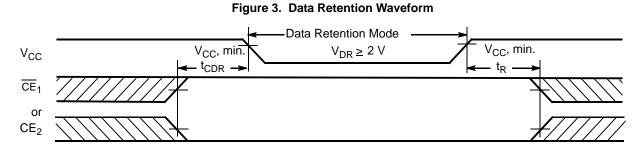
## AC Test Loads and Waveforms







## Data Retention Waveform



## **Data Retention Characteristics**

Over the Operating Range

Parameter Description		Condition	Min	Тур	Max	Unit	
V <sub>DR</sub>	V <sub>CC</sub> for data retention				-	-	V
I <sub>CCDR</sub> Data retention curre		$\begin{array}{l} \frac{V_{CC}}{CE} = V_{DR} = 2.0 \text{ V}, \\ \overline{CE}_1 \geq V_{CC} - 0.3 \text{ V}, \text{ or} \\ CE_2 \leq 0.3 \text{ V}, \\ V_{IN} \geq V_{CC} - 0.3 \text{ V or}, \\ V_{IN} \leq 0.3 \text{ V} \end{array} \right.$ Automotive-E		-	1.5	25	μA
t <sub>CDR</sub>	Chip deselect to data retention time			0	-	-	ns
t <sub>R</sub>	Operation recovery time			70	-	-	ns



## **Switching Characteristics**

Over the Operating Range

Parameter [6]	Description	CY6212	CY621282BN-70	
Parameter	Description	Min	Max	Unit
Read Cycle				
t <sub>RC</sub>	Read cycle time	70	-	ns
t <sub>AA</sub>	Address to data valid	-	70	ns
t <sub>OHA</sub>	Data hold from address change	5	-	ns
t <sub>ACE</sub>	CE <sub>1</sub> LOW to data valid, CE <sub>2</sub> HIGH to data valid	-	70	ns
t <sub>DOE</sub>	OE LOW to data valid	-	35	ns
t <sub>LZOE</sub>	OE LOW to Low Z <sup>[7]</sup>	0	-	ns
t <sub>HZOE</sub>	OE HIGH to High Z <sup>[7, 8]</sup>	-	25	ns
t <sub>LZCE</sub>	CE <sub>1</sub> LOW to Low Z, CE <sub>2</sub> HIGH to Low Z <sup>[7]</sup>	5	-	ns
t <sub>HZCE</sub>	CE <sub>1</sub> HIGH to High Z, CE <sub>2</sub> LOW to High Z <sup>[7, 8]</sup>	-	25	ns
t <sub>PU</sub>	CE <sub>1</sub> LOW to Power-up, CE <sub>2</sub> HIGH to power-up	0	-	ns
t <sub>PD</sub>	CE <sub>1</sub> HIGH to Power-down, CE <sub>2</sub> LOW to power-down	-	70	ns
Write Cycle <sup>[9]</sup>				
t <sub>WC</sub>	Write cycle time	70	-	ns
t <sub>SCE</sub>	CE <sub>1</sub> LOW to Write End, CE <sub>2</sub> HIGH to write end	60	-	ns
t <sub>AW</sub>	Address set-up to write end	60	-	ns
t <sub>HA</sub>	Address hold from write end	0	-	ns
t <sub>SA</sub>	Address set-up to write start	0	-	ns
t <sub>PWE</sub>	WE pulse width	50	-	ns
t <sub>SD</sub>	Data set-up to write end	30	-	ns
t <sub>HD</sub>	Data Hold from write end	0	-	ns
t <sub>LZWE</sub>	WE HIGH to Low Z <sup>[7]</sup>	5	-	ns
t <sub>HZWE</sub>	WE LOW to High Z <sup>[7, 8]</sup>	-	25	ns

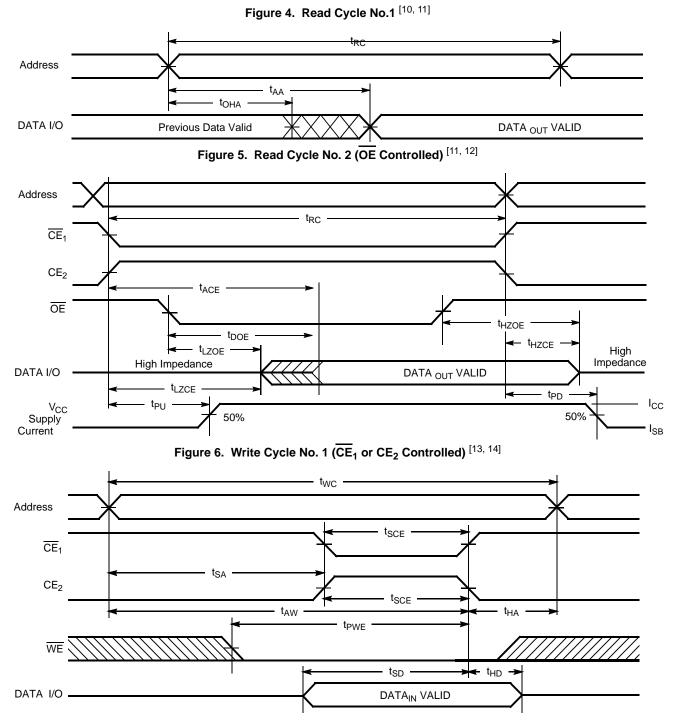
Notes

- Notes
  6. Test conditions assume signal transition time of 5 ns or less, timing reference levels of 1.5 V, input pulse levels of 0 to 3.0 V, and output loading of the specified I<sub>OL</sub>/I<sub>OH</sub> and 100-pF load capacitance.
  7. At any given temperature and voltage condition, t<sub>HZCE</sub> is less than t<sub>LZCE</sub>, t<sub>HZOE</sub> is less than t<sub>LZCE</sub>, and t<sub>HZWE</sub> for any given device.
  8. t<sub>HZOE</sub>, t<sub>HZCE</sub>, and t<sub>HZWE</sub> are specified with a load capacitance of <u>5 p</u>F as in (b) of Figure 2 on page 5. <u>Transition is measured ±500 mV</u> from steady-state voltage.
  9. The internal write time of the memory is defined by the overlap of CE<sub>1</sub> LOW, CE<sub>2</sub> HIGH, and WE LOW. CE<sub>1</sub> and WE must be LOW and CE<sub>2</sub> HIGH to initiate a write, and the transition of any of these signals can terminate the write. The input data set-up and hold timing should be referenced to the leading edge of the signal that terminate write

- terminates the write.



### **Switching Waveforms**



#### Notes

- 10. <u>Dev</u>ice is continuously selected.  $\overline{OE}$ ,  $\overline{CE}_1 = V_{IL}$ ,  $CE_2 = V_{IH}$ .
- 11. WE is HIGH for read cycle.
- 12. Address valid prior to or coincident with  $\overline{CE}_1$  transition LOW and  $CE_2$  transition HIGH. 13. Data I/O is high impedance if  $\overline{OE} = V_{IH}$ . 14. If  $\overline{CE}_1$  goes HIGH or  $CE_2$  goes LOW simultaneously with  $\overline{WE}$  going HIGH, the output remains in a high-impedance state.



## Switching Waveforms (continued)

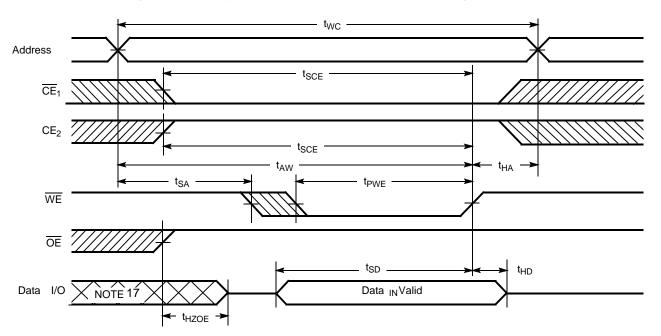
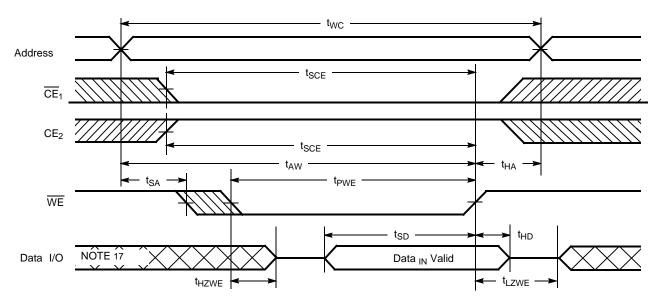


Figure 7. Write Cycle No. 2 (WE Controlled, OE HIGH during Write) <sup>[15, 16]</sup>





#### Notes

15. Data I/O is high impedance if  $\overline{OE} = V_{IH}$ . 16. If  $\overline{CE}_1$  goes HIGH or  $CE_2$  goes LOW simultaneously with  $\overline{WE}$  going HIGH, the output remains in a high-impedance state. 17. During this period the I/Os are in the output state and input signals should not be applied.



## **Truth Table**

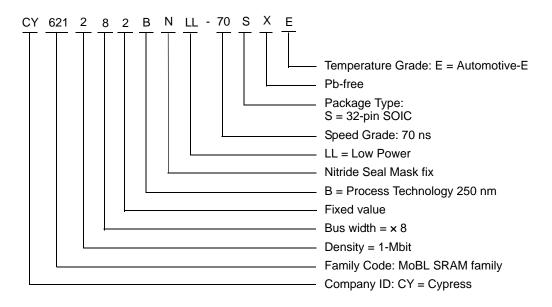
CE <sub>1</sub>	CE <sub>2</sub>	OE	WE	I/O <sub>0</sub> –I/O <sub>7</sub>	Mode	Power
Н	Х	Х	Х	High Z	Power-down	Standby (I <sub>SB</sub> )
Х	L	Х	Х	High Z	Power-down	Standby (I <sub>SB</sub> )
L	н	L	Н	Data out	Read	Active (I <sub>CC</sub> )
L	н	Х	L	Data in	Write	Active (I <sub>CC</sub> )
L	Н	Н	Н	High Z	Selected, Outputs disabled	Active (I <sub>CC</sub> )

## **Ordering Information**

Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
70	CY621282BNLL-70SXE	51-85081	32-pin 450-Mil SOIC (Pb-free)	Automotive-E

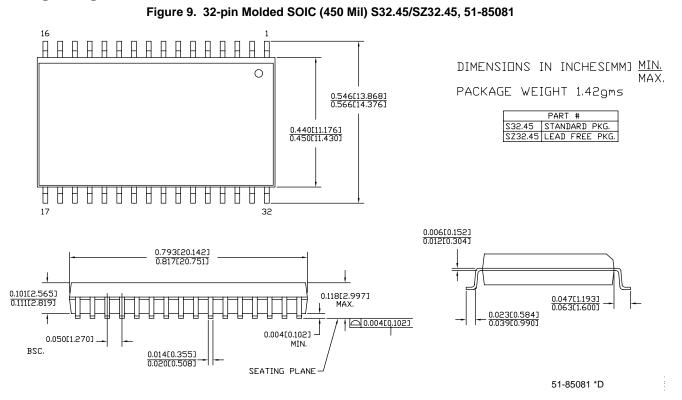
Please contact your local Cypress sales representative for availability of these parts.

### **Ordering Code Definitions**





## **Package Diagrams**





## Acronyms

Acronym Description	
CE	chip enable
CMOS complementary metal oxide semiconductor	
I/O	input/output
OE	output enable
SOIC	small outline integrated circuit
SRAM	static random access memory
TTL	transistor-transistor logic
WE	write enable

## **Document Conventions**

### Units of Measure

Symbol	Unit of Measure
°C	degree Celsius
MHz	Mega Hertz
μA	microamperes
μS	microseconds
mA	milliamperes
mV	millivolts
mW	milliwatts
ns	nanoseconds
Ω	ohms
%	percent
pF	picofarad
V	Volts
W	Watts



## **Document History Page**

	Document Title: CY621282BN MoBL <sup>®</sup> Automotive, 1-Mbit (128 K × 8) Static RAM Document Number: 001-65526					
REV.	ECN NO.         Issue Date         Orig. of Change         Description of Change		Description of Change			
**	3115909	01/06/2011	RAME	New Data Sheet		
*A	3288690	06/21/2011	RAME	Removed the Note "For best-practice recommendations, please refer to the Cypress application note "System Design Guidelines" on http://www.cypress.com." and its reference in Functional Description. Updated in new template.		
*В	3538379	03/05/2012	TAVA	Updated Electrical Characteristics table Updated Switching Waveforms Updated Package Diagrams		



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